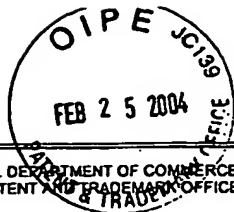


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 245841US2		SERIAL NO. 10/722,527	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Simon RYDER			
				FILING DATE November 28, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
MK	AA	6,488,034	10/15/2002	M.- G. WANG, et al.			
	AB						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
MK	AO	WO 02/35248	05/02/2002	WIPO			
	AP						
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	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	S. A. RYDER, Conf. Record of 2002 IEEE Int. Symp. on Elect. Insulation, pages 187-190, XP-001162794, "METHODS FOR COMPARING FREQUENCY RESPONSE ANALYSIS MEASUREMENTS", April 2002					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>M. Aravindhaya</i>					Date Considered <i>1/27/05</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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SHEET 1 OF 1

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LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Simon RYDER			
				FILING DATE November 28, 2003		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MX</i>	AA	6,466,034	10/15/2002	M.- G. WANG, et al.			
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>MX</i>	AO	WO 02/35248	05/02/2002	WIPO			
	AP						
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	AT						
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	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>MX</i>	AW	S. A. RYDER, Conf. Record of 2002 IEEE Int. Symp. on Elect. Insulation, pages 187-190, XP-001162794, "METHODS FOR COMPARING FREQUENCY RESPONSE ANALYSIS MEASUREMENTS", April 2002					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>M. Kramshova</i>				Date Considered <i>8/18/05</i>			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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